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Supplementary Information

Probing Composition Distributions in Nanoalloy Catalysts with Correlative Electron Microscopy

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Table S1. Composition of the AuPd nanoalloys as determined ed by ICP-AES.

	Pd	Relative	Au	Relative	Pd:Au wt
Catalyst	content	error	content	error	ratio
	wt%	%	wt%	%	
	M_{Pd}		M_{Au}		
1wt%AuPd/TiO ₂ (PVP)	0.39	2.5	0.4	2.5	0.98
1wt%AuPd/TiO ₂ (PVA)	0.37	5%	0.35	9%	1.05

^a The sample for ICP-AES was obtained by digesting the catalysts in *aqua regia*. The solution was then filtered and diluted down to a metal concentration of about 10ppm before being tested.

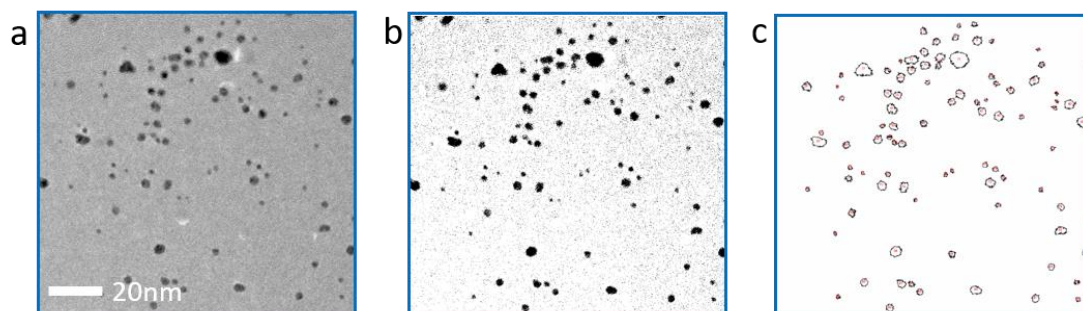


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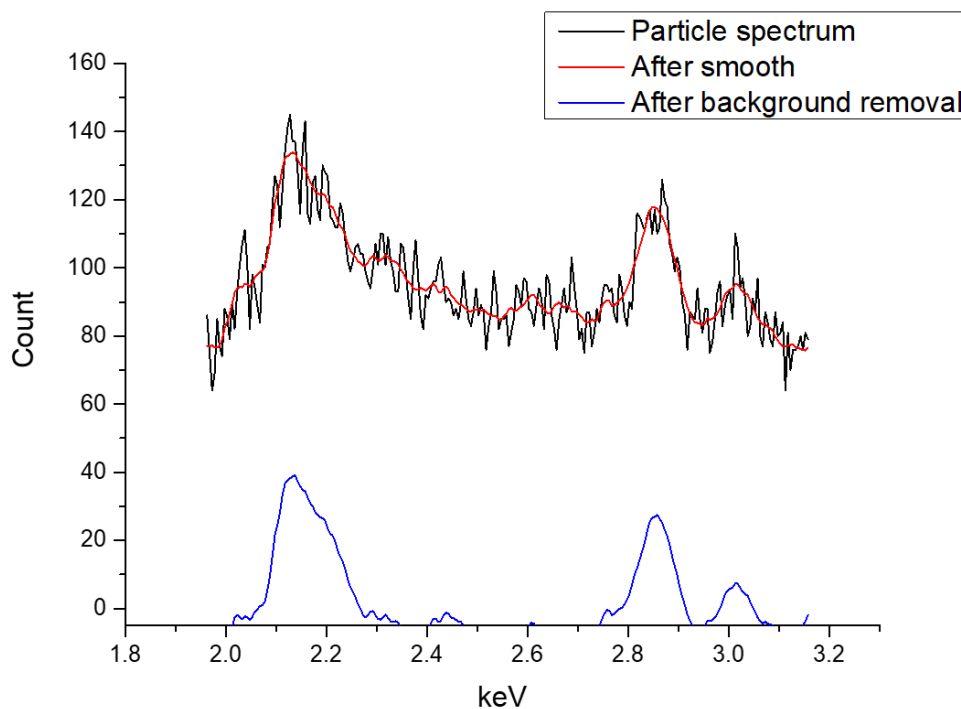


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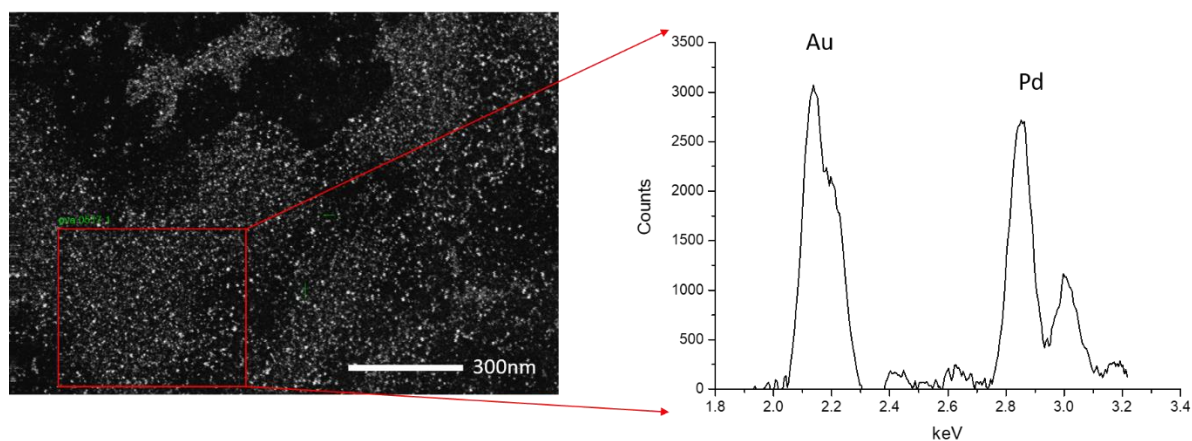


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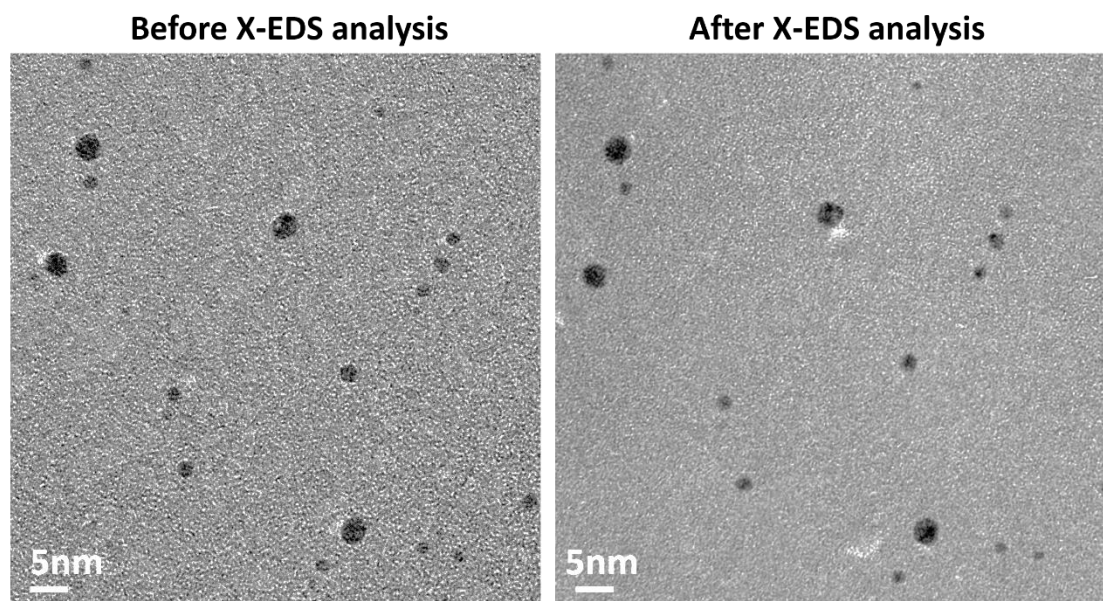


Figure S4. BF-TEM images acquired before and after the X-EDS analysis, showing no sign of particle growth provided the particles were reasonably isolated, which is a pre-requirement for the SEM analysis in the first place.

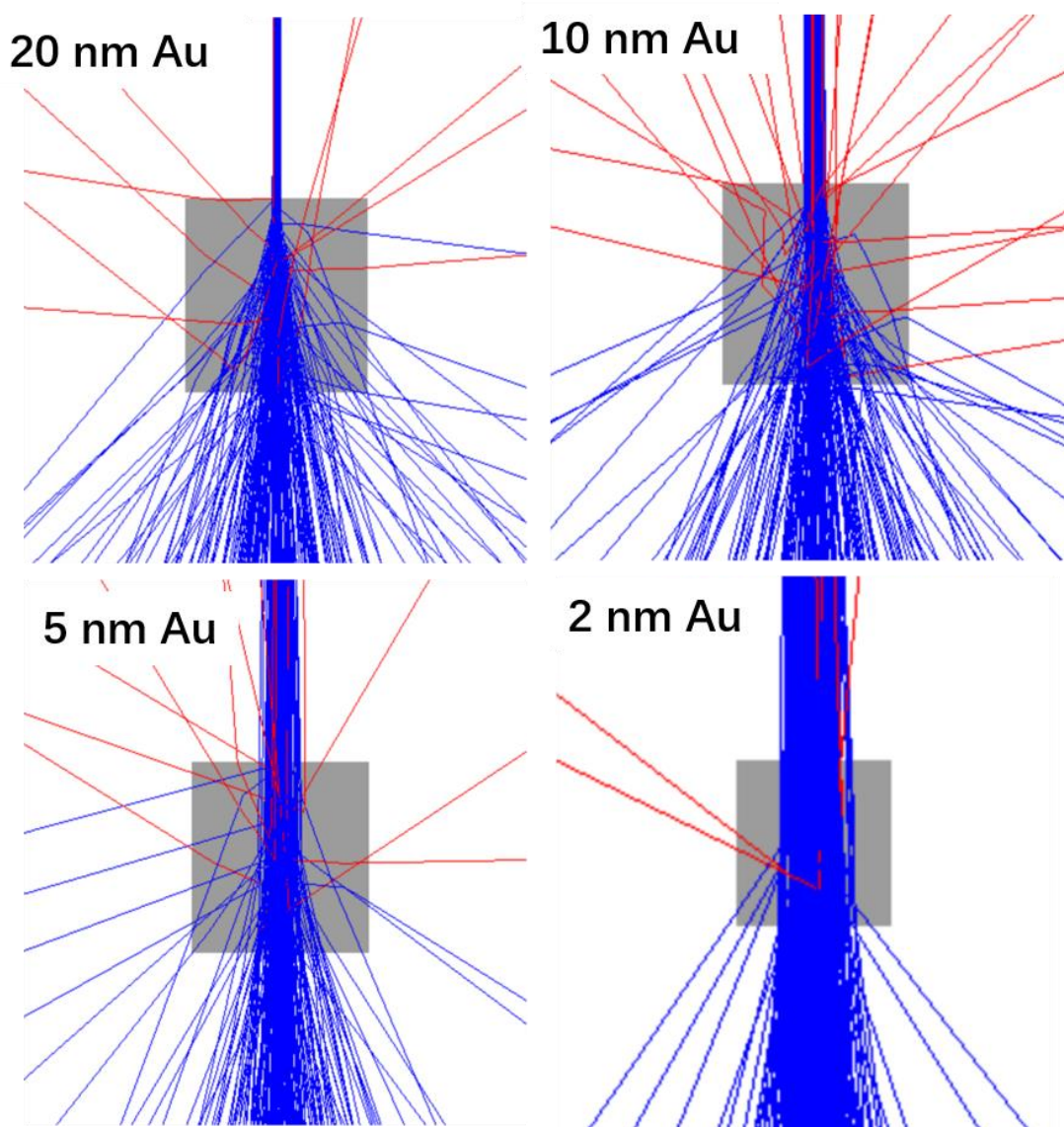


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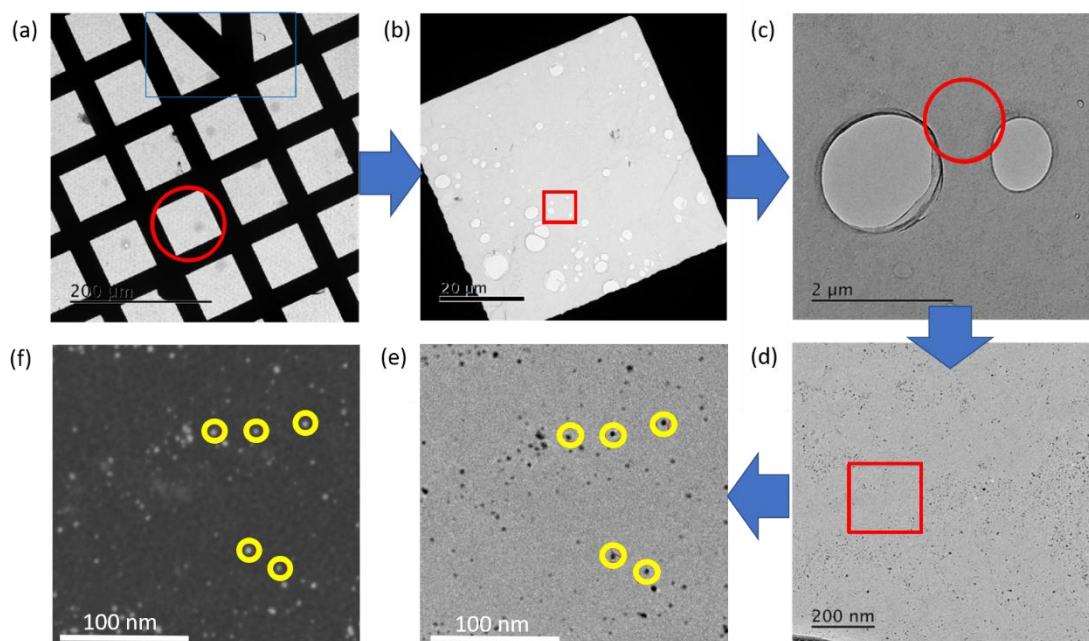


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